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What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Obsolete
Core Processor	ARM9®
Core Size	16/32-Bit
Speed	96MHz
Connectivity	CANbus, EBI/EMI, Ethernet, I ² C, IrDA, Microwire, SPI, SSI, SSP, UART/USART, USB
Peripherals	Brown-out Detect/Reset, DMA, Motor Control PWM, POR, PWM, WDT
Number of I/O	80
Program Memory Size	2MB (2M x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	96K x 8
Voltage - Supply (Vcc/Vdd)	1.65V ~ 2V
Data Converters	A/D 8x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	128-LQFP
Supplier Device Package	-
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/str912faw47x6

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3.5 SRAM (64 Kbytes or 96 Kbytes)

A 32-bit wide SRAM resides on the CPU's Data TCM (D-TCM) interface, providing single-cycle data accesses. As shown in [Figure 1](#), the D-TCM shares SRAM access with the Advanced High-performance Bus (AHB). Sharing is controlled by simple arbitration logic to allow the DMA unit on the AHB to also access the SRAM.

3.5.1 Arbitration

Zero-wait state access occurs for either the D-TCM or the AHB when only one of the two is requesting SRAM. When both request SRAM simultaneously, access is granted on an interleaved basis so neither requestor is starved, granting one 32-bit word transfer to each requestor before relinquishing SRAM to the other. When neither the D-TCM or the AHB are requesting SRAM, the arbiter leaves access granted to the most recent user (if D-TCM was last to use SRAM then the D-TCM will not have to arbitrate to get access next time).

The CPU may execute code from SRAM through the AHB. There are no wait states as long as the D-TCM is not contending for SRAM access and the AHB is not sharing bandwidth with peripheral traffic. The ARM966E-S CPU core has a small pre-fetch queue built into this instruction path through the AHB to look ahead and fetch instructions during idle bus cycles.

3.5.2 Battery backup

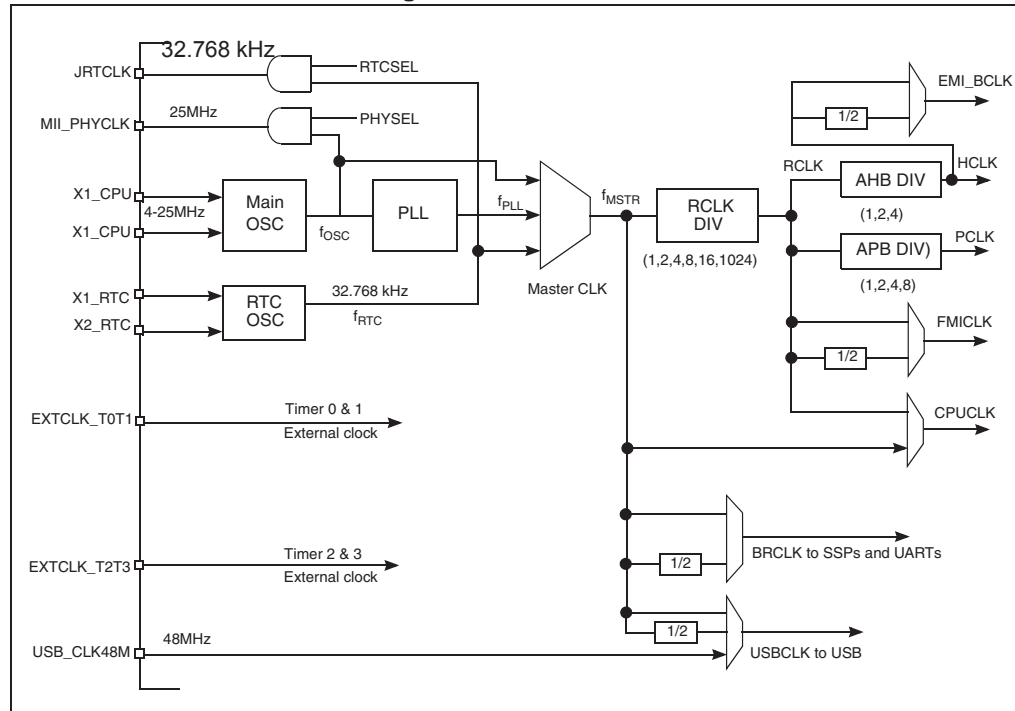
When a battery is connected to the designated battery backup pin (VBATT), SRAM contents are automatically preserved when the operating voltage on the main digital supplies (VDD and VDDQ) are lost or sag below the LVD threshold. Automatic switchover to SRAM can be disabled by firmware if it is desired that the battery will power only the RTC and not the SRAM during standby.

3.6 DMA data movement

DMA channels on the Advanced High-performance Bus (AHB) take full advantage of the separate data path provided by the Harvard architecture, moving data rapidly and largely independent of the instruction path. There are two DMA units, one is dedicated to move data between the Ethernet interface and SRAM, the other DMA unit has eight programmable channels with 14 request signals to service other peripherals and interfaces (USB, SSP, ADC, UART, Timers, EMI, and external request pins). Both single word and burst DMA transfers are supported. Memory-to-memory transfers are supported in addition to memory-peripheral transfers. DMA access to SRAM is shared with D-TCM accesses, and arbitration is described in [Section 3.5.1](#). Efficient DMA transfers are managed by firmware using linked list descriptor tables. Of the 16 DMA request signals, two are assigned to external inputs. The DMA unit can move data between external devices and resources inside the STR91xFA through the EMI bus.

As an option, there are a number of peripherals that do not have to receive a clock sourced from the CCU. The USB interface can receive an external clock on pin P2.7, TIM timers TIM0/ TIM1 can receive an external clock on pin P2.4, and timers TIM2/TIM3 on pin P2.5.

Figure 2. Clock control



3.10.2 Reference clock (RCLK)

The main clock (f_{MSTR}) can be divided to operate at a slower frequency reference clock (RCLK) for the ARM core and all the peripherals. The RCLK provides the divided clock for the ARM core, and feeds the dividers for the AHB, APB, External Memory Interface, and FMI units.

3.10.3 AHB clock (HCLK)

The RCLK can be divided by 1, 2 or 4 to generate the AHB clock. The AHB clock is the bus clock for the AHB bus and all bus transfers are synchronized to this clock. The maximum HCLK frequency is 96 MHz.

3.10.4 APB clock (PCLK)

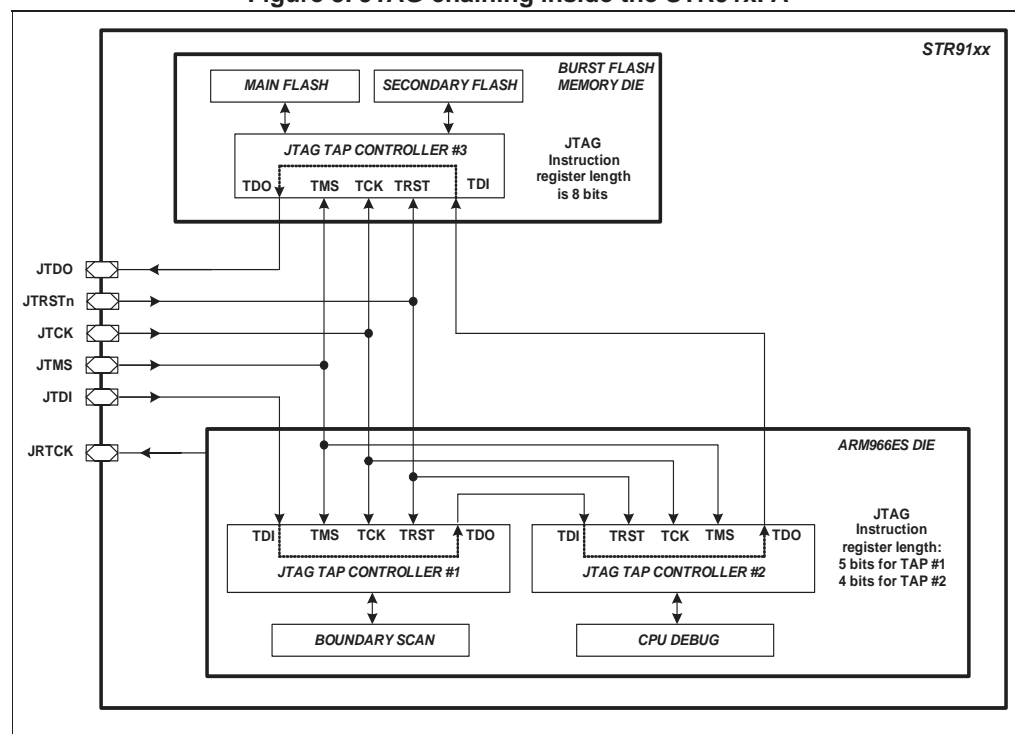
The RCLK can be divided by 1, 2, 4 or 8 to generate the APB clock. The APB clock is the bus clock for the APB bus and all bus transfers are synchronized to this clock. Many of the peripherals that are connected to the AHB bus also use the PCLK as the source for external bus data transfers. The maximum PCLK frequency is 48 MHz.

three TAPs are daisy-chained, only one TAP will converse on the JTAG bus at any given time while the other two TAPs are in BYPASS mode. The TAP positioning order within this JTAG chain is the boundary scan TAP first, followed by the ARM debug TAP, followed by the Flash TAP. All three TAP controllers are reset simultaneously by one of two methods:

- A chip-level global reset, caused only by a Power-On-Reset (POR) or a Low Voltage Detect (LVD).
- A reset command issued by the external JTAG test equipment. This can be the assertion of the JTAG JTRSTn input pin on the STR91xFA or a JTAG reset command shifted into the STR91xFA serially.

This means that chip-level system resets from watchdog time-out or the assertion of RESET_INn pin do not affect the operation of any JTAG TAP controller. Only global resets effect the TAPs.

Figure 3. JTAG chaining inside the STR91xFA



3.15.1 In-system-programming

The JTAG interface is used to program or erase all memory areas of the STR91xFA device. The pin RESET_INn must be asserted during ISP to prevent the CPU from fetching invalid instructions while the Flash memories are being programmed.

Note that the 32 bytes of OTP memory locations cannot be erased by any means once programmed by JTAG ISP or the CPU.

3.16 Embedded trace module (ARM ETM9, v. r2p2)

The ETM9 interface provides greater visibility of instruction and data flow happening inside the CPU core by streaming compressed data at a very high rate from the STR91xFA through a small number of ETM9 pins to an external Trace Port Analyzer (TPA) device. The TPA is connected to a host computer using USB, Ethernet, or other high-speed channel. Real-time instruction flow and data activity can be recorded and later formatted and displayed on the host computer running debugger software, and this software is typically integrated with the debug software used for EmbeddedICE-RT functions such as single-step, breakpoints, etc. Tracing may be triggered and filtered by many sources, such as instruction address comparators, data watchpoints, context ID comparators, and counters. State sequencing of up to three triggers is also provided. TPA hardware is commercially available and operates with debugging software tools.

The ETM9 interface is nine pins total, four of which are data lines, and all pins can be used for GPIO after tracing is no longer needed. The ETM9 interface is used in conjunction with the JTAG interface for trace configuration. When tracing begins, the ETM9 engine compresses the data by various means before broadcasting data at high speed to the TPA over the four data lines. The most common ETM9 compression technique is to only output address information when the CPU branches to a location that cannot be inferred from the source code. This means the host computer must have a static image of the code being executed for decompressing the ETM9 data. Because of this, self-modified code cannot be traced.

3.17 Ethernet MAC interface with DMA

STR91xFA devices in 128-pin and 144-ball packages provide an IEEE-802.3-2002 compliant Media Access Controller (MAC) for Ethernet LAN communications through an industry standard Medium Independent Interface (MII). The STR91xFA requires an external Ethernet physical interface device (PHY) to connect to the physical LAN bus (twisted-pair, fiber, etc.). The PHY is connected to the STR91xFA MII port using as many as 18 signals (see pins which have signal names MII_* in [Table 8](#)).

The MAC corresponds to the OSI Data Link layer and the PHY corresponds to the OSI Physical layer. The STR91xFA MAC is responsible for:

- Data encapsulation, including frame assembly before transmission, and frame parsing/error detection during and after reception.
- Media access control, including initiation of frame transmission and recover from transmission failure.

The STR91xFA MAC includes the following features:

- Supports 10 and 100 Mbps rates
- Tagged MAC frame support (VLAN support)
- Half duplex (CSMA/CD) and full duplex operation
- MAC control sublayer (control frames) support
- 32-bit CRC generation and removal
- Several address filtering modes for physical and multicast address (multicast and group addresses)
- 32-bit status code for each transmitted or received frame
- Internal FIFOs to buffer transmit and receive frames. Transmit FIFO depth is 4 words (32 bits each), and the receive FIFO is 16 words deep.

A 32-bit burst DMA channel residing on the AHB is dedicated to the Ethernet MAC for high-speed data transfers, side-stepping the CPU for minimal CPU impact during transfers. This DMA channel includes the following features:

- Direct SRAM to MAC transfers of transmit frames with the related status, by descriptor chain
- Direct MAC to SRAM transfers of receive frames with the related status, by descriptor chain
- Open and Closed descriptor chain management

3.18 USB 2.0 slave device interface with DMA

The STR91xFA provides a USB slave controller that implements both the OSI Physical and Data Link layers for direct bus connection by an external USB host on pins USBDP and USBPN. The USB interface detects token packets, handles data transmission and reception, and processes handshake packets as required by the USB 2.0 standard.

The USB slave interface includes the following features:

- Supports USB low and full-speed transfers (12 Mbps), certified to comply with the USB 2.0 specification
- Supports isochronous, bulk, control, and interrupt endpoints
- Configurable number of endpoints allowing a mixture of up to 20 single-buffered monodirectional endpoints or up to 10 double-buffered bidirectional endpoints
- Dedicated, dual-port 2 Kbyte USB Packet Buffer SRAM. One port of the SRAM is connected by a Packet Buffer Interface (PBI) on the USB side, and the CPU connects to the other SRAM port.
- CRC generation and checking
- NRZI encoding-decoding and bit stuffing
- USB suspend resume operations

3.22.1 DMA

A programmable DMA channel may be assigned by CPU firmware to service each SSP channel for fast and direct transfers between the SSP bus and SRAM with little CPU involvement. Both DMA single-transfers and DMA burst-transfers are supported for transmit and receive. Burst transfers require that FIFOs are enabled.

3.23 General purpose I/O

There are up to 80 GPIO pins available on 10 I/O ports for 128-pin and 144-ball devices, and up to 40 GPIO pins on 5 I/O ports for 80-pin devices. Each and every GPIO pin by default (during and just after a reset condition) is in high-impedance input mode, and some GPIO pins are additionally routed to certain peripheral function inputs. CPU firmware may initialize GPIO pins to have alternate input or output functions as listed in [Table 8](#). At any time, the logic state of any GPIO pin may be read by firmware as a GPIO input, regardless of its reassigned input or output function.

Bit masking is available on each port, meaning firmware may selectively read or write individual port pins, without disturbing other pins on the same port during a write.

Firmware may designate each GPIO pin to have open-drain or push-pull characteristics.

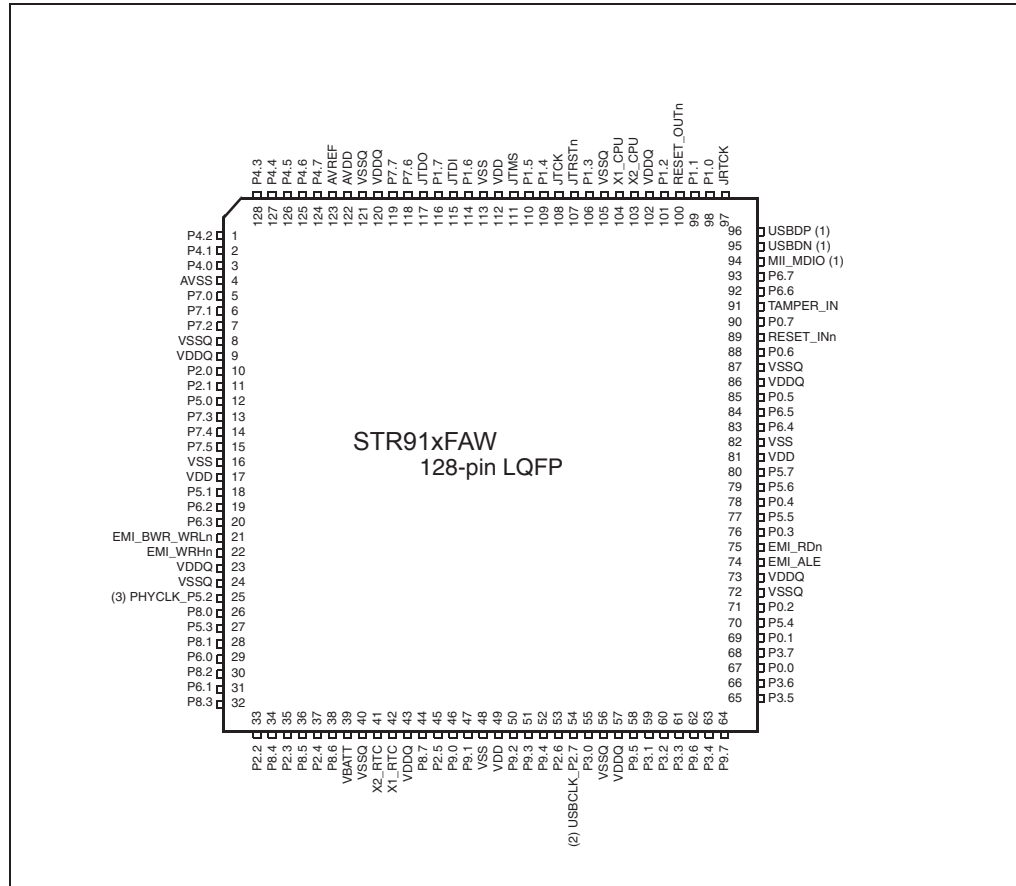
All GPIO pins are 5 V tolerant, meaning they can drive a voltage level up to VDDQ, and can be safely driven by a voltage up to 5 V.

3.24 A/D converter (ADC) with DMA

The STR91xFA provides an eight-channel, 10-bit successive approximation analog-to-digital converter. The ADC input pins are multiplexed with other functions on Port 4 as shown in [Table 8](#). Following are the major ADC features:

- Fast conversion time, as low as 0.7 μ sec
- Accuracy. Integral and differential non-linearity are typically within 4 conversion counts.
- 0 to 3.6 V input range. External reference voltage input pin (AVREF) available on 128-pin packages for better accuracy on low-voltage inputs. See [Table 11: Operating conditions](#), for restrictions to the relative voltage levels of VDDQ, AVDD, AVREF, and AVREF_AVDD.
- CPU Firmware may convert one ADC input channel at a time, or it has the option to set the ADC to automatically scan and convert all eight ADC input channels sequentially before signalling an end-of-conversion
- Automatic continuous conversion mode is available for any number of designated ADC input channels
- Analog watchdog mode provides automatic monitoring of any ADC input, comparing it against two programmable voltage threshold values. The ADC unit will set a flag or it will interrupt the CPU if the input voltage rises above the higher threshold, or drops below the lower threshold.
- The ADC unit goes to stand-by mode (very low-current consumption) after any reset event. CPU firmware may also command the ADC unit to stand-by mode at any time.
- ADC conversion can be started or triggered by software command as well as triggers from Timer/Counter (TIM), Motor Controller and input from external pin.

Figure 8. STR91xFAW 128-pin package pinout



1. NU (Not Used) on STR910FAW devices. Pin 95 is not connected, pin 96 must be pulled up by a 1.5Kohm resistor to VDDQ.
2. No USBCLK function on STR910FAW devices.
3. No PHYCLK function on STR910FAW devices.

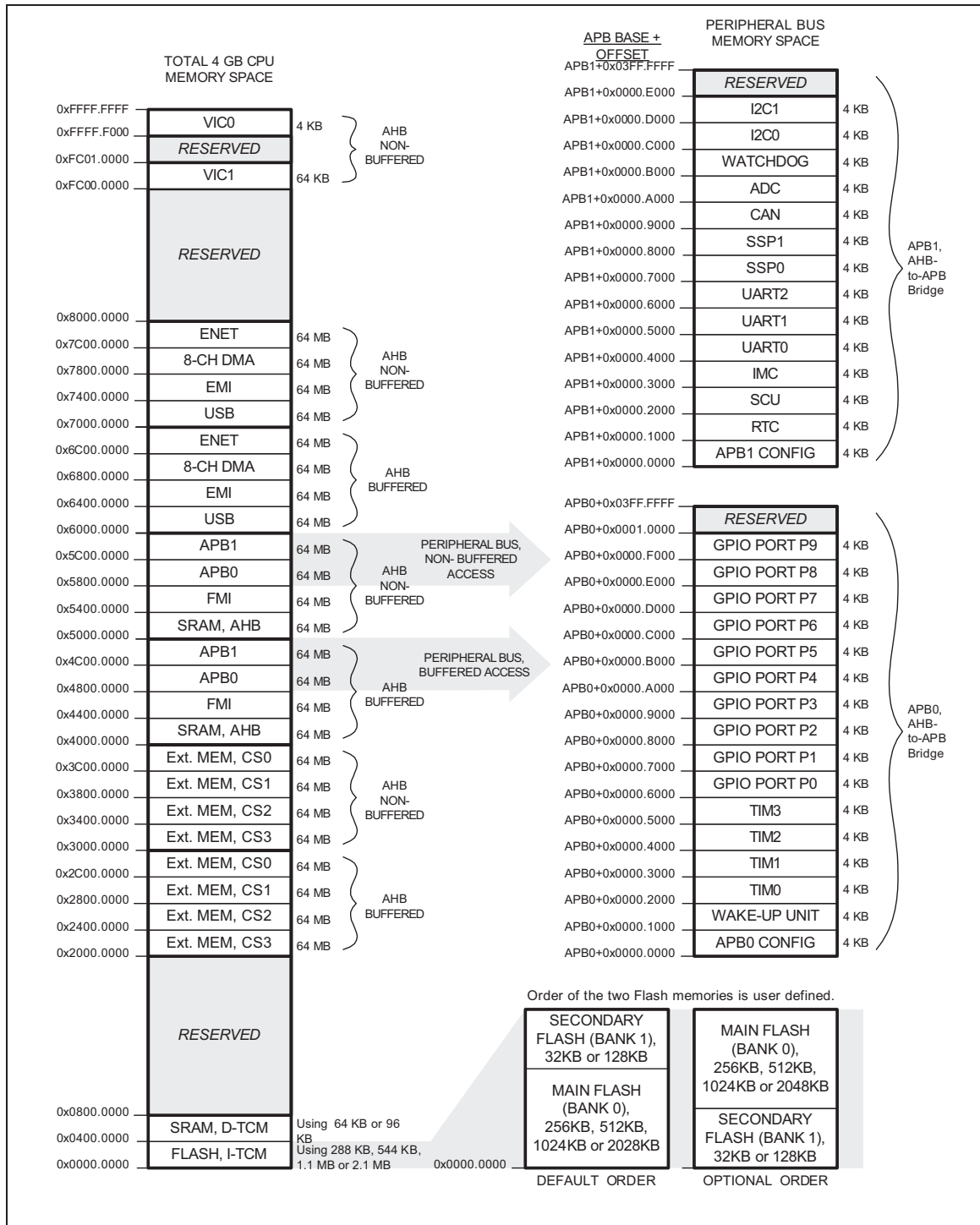
Table 8. Device pin description (continued)

Package			Pin name	Signal type	Default pin function	Default input function	Alternate functions			
LQFP80	LQFP128	LFBGA144					Alternate input 1	Alternate output 1	Alternate output 2	Alternate output 3
12	18	F6	P5.1	I/O	GPIO_5.1, GP Input, HiZ	EXINT9, External Intr	UART0_RxD, UART rcv data	GPIO_5.1, GP Output	CAN_TX, CAN Tx data	UART2_TX, UART xmit data
17	25	K1	PHYCLK_P5.2	I/O	GPIO_5.2, GP Input, HiZ	EXINT10, External Intr	UART2_RxD, UART rcv data	GPIO_5.2, GP Output	MII_PHYCLK, 25Mhz to PHY	TIM3_OCMP1, Out comp/PWM
18	27	H2	P5.3	I/O	GPIO_5.3, GP Input, HiZ	EXINT11, External Intr	ETM_EXTRIG, ETM ext. trigger	GPIO_5.3, GP Output	MII_TX_EN, MAC xmit enbl	TIM2_OCMP1, Out comp/PWM
44	70	J12	P5.4	I/O	GPIO_5.4, GP Input, HiZ	EXINT12, External Intr	SSP0_SCLK, SSP slv clk in	GPIO_5.4, GP Output	SSP0_SCLK, SSP mstr clk out	EMI_CS0n, EMI Chip Select
47	77	H11	P5.5	I/O	GPIO_5.5, GP Input, HiZ	EXINT13, External Intr	SSP0_MOSI, SSP slv dat in	GPIO_5.5, GP Output	SSP0_MOSI, SSP mstr dat out	EMI_CS1n, EMI Chip Select
48	79	H9	P5.6	I/O	GPIO_5.6, GP Input, HiZ	EXINT14, External Intr	SSP0_MISO, SSP mstr dat in	GPIO_5.6, GP Output	SSP0_MISO, SSP slv data out	EMI_CS2n, EMI Chip Select
49	80	G12	P5.7	I/O	GPIO_5.7, GP Input, HiZ	EXINT15, External Intr	SSP0_NSS, SSP slv select in	GPIO_5.7, GP Output	SSP0_NSS, SSP mstr sel out	EMI_CS3n, EMI Chip Select
19	29	H4	P6.0	I/O	GPIO_6.0, GP Input, HiZ	EXINT16, External Intr	TIM0_ICAP1, Input Capture	GPIO_6.0, GP Output	TIM0_OCMP1, Out comp/PWM	MC_UH, IMC phase U hi
20	31	J3	P6.1	I/O	GPIO_6.1, GP Input, HiZ	EXINT17, External Intr	TIM0_ICAP2, Input Capture	GPIO_6.1, GP Output	TIM0_OCMP2, Out comp	MC_UL, IMC phase U lo
13	19	G2	P6.2	I/O	GPIO_6.2, GP Input, HiZ	EXINT18, External Intr	TIM1_ICAP1, Input Capture	GPIO_6.2, GP Output	TIM1_OCMP1, Out comp/PWM	MC_VH, IMC phase V hi
14	20	G3	P6.3	I/O	GPIO_6.3, GP Input, HiZ	EXINT19, External Intr	TIM1_ICAP2, Input Capture	GPIO_6.3, GP Output	TIM1_OCMP2, Out comp	MC_VL, IMC phase V lo
52	83	G8	P6.4	I/O	GPIO_6.4, GP Input, HiZ	EXINT20, External Intr	TIM2_ICAP1, Input Capture	GPIO_6.4, GP Output	TIM2_OCMP1, Out comp/PWM	MC_WH, IMC phase W hi
53	84	G7	P6.5	I/O	GPIO_6.5, GP Input, HiZ	EXINT21, External Intr	TIM2_ICAP2, Input Capture	GPIO_6.5, GP Output	TIM2_OCMP2, Out comp	MC_WL, IMC phase W lo
57	92	E9	P6.6	I/O	GPIO_6.6, GP Input, HiZ	EXINT22_TRIG, Ext Intr & Tach	UART0_RxD, UART rcv data	GPIO_6.6, GP Output	TIM3_OCMP1, Out comp/PWM	ETM_TRCLK, ETM trace clock
58	93	D12	P6.7	I/O	GPIO_6.7, GP Input, HiZ	EXINT23_STOP, Ext Intr & Estop	ETM_EXTRIG, ETM ext. trigger	GPIO_6.7, GP Output	TIM3_OCMP2, Out comp	UART0_TX, UART xmit data
-	5	D1	P7.0	I/O	GPIO_7.0, GP Input, HiZ	EXINT24, External Intr	TIM0_ICAP1, Input Capture	GPIO_7.0, GP Output	8b) EMI_A0, 16b) EMI_A16	ETM_PCK0, ETM Packet
-	6	D2	P7.1	I/O	GPIO_7.1, GP Input, HiZ	EXINT25, External Intr	TIM0_ICAP2, Input Capture	GPIO_7.1, GP Output	8b) EMI_A1, 16b) EMI_A17	ETM_PCK1, ETM Packet
-	7	B1	P7.2	I/O	GPIO_7.2, GP Input, HiZ	EXINT26, External Intr	TIM2_ICAP1, Input Capture	GPIO_7.2, GP Output	8b) EMI_A2, 16b) EMI_A18	ETM_PCK2, ETM Packet
-	13	F1	P7.3	I/O	GPIO_7.3, GP Input, HiZ	EXINT27, External Intr	TIM2_ICAP2, Input Capture	GPIO_7.3, GP Output	8b) EMI_A3, 16b) EMI_A19	ETM_PCK3, ETM Packet
-	14	G1	P7.4	I/O	GPIO_7.4, GP Input, HiZ	EXINT28, External Intr	UART0_RxD, UART rcv data	GPIO_7.4, GP Output	8b) EMI_A4, 16b) EMI_A20	EMI_CS3n, EMI Chip Select
-	15	E5	P7.5	I/O	GPIO_7.5, GP Input, HiZ	EXINT29, External Intr	ETM_EXTRIG, ETM ext. trigger	GPIO_7.5, GP Output	8b) EMI_A5, 16b) EMI_A21	EMI_CS2n, EMI Chip Select

Table 8. Device pin description (continued)

Package			Pin name	Signal type	Default pin function	Default input function	Alternate functions			
LQFP80	LQFP128	LFPGA144					Alternate input 1	Alternate output 1	Alternate output 2	Alternate output 3
-	21	G4	EMI_BWR_WRLn	O	EMI byte write strobe (8 bit mode) or low byte write strobe (16 bit mode) Can also be configured as EMI_LBn in BGA package			N/A		
-	22	H1	EMI_WRHn	O	EMI high byte write strobe (16-bit mode) Can also be configured as EMI_UBn in BGA package			N/A		
-	74	J10	EMI_ALE	O	EMI address latch enable (mux mode)			N/A		
-	75	J9	EMI_RDn	O	EMI read strobe			N/A		
-	-	H8	EMI_BAA _n	O	EMI Burst address advance			N/A		
-	-	K8	EMI_WAIT _n	I	EMI Wait input for burst mode device			N/A		
-	-	M8	EMI_BCLK	O	EMI bus clock			N/A		
-	-	A12	EMI_WEn	O	EMI write enable			N/A		
-	91	E10	TAMPER_IN	I	Tamper detection input			N/A		
-	94	D11	MII_MDIO	I/O	MAC/PHY management data line			N/A		
59	95	D10	USBDN	I/O	USB data (-) bus connect			N/A		
60	96	C11	USBDP	I/O	USB data (+) bus connect			N/A		
56	89	C12	RESET_IN _n	I	External reset input			N/A		
62	100	A9	RESET_OUT _n	O	Global or System reset output			N/A		
65	104	A10	X1_CPU	I	CPU oscillator or crystal input			N/A		
64	103	A11	X2_CPU	O	CPU crystal connection			N/A		

Figure 9. STR91xFA memory map



7.9.5 Static latch-up

Two complementary static tests are required on 10 parts to assess the latch-up performance.

- A supply overvoltage (applied to each power supply pin) and
- A current injection (applied to each input, output and configurable I/O pin) are performed on each sample.

This test conforms to the EIA/JESD 78 IC latch-up standard. For more details, refer to the application note AN1181.

7.9.6 Designing hardened software to avoid noise problems

EMC characterization and optimization are performed at component level with a typical application environment and simplified MCU software. It should be noted that good EMC performance is highly dependent on the user application and the software in particular.

Therefore it is recommended that the user applies EMC software optimization and prequalification tests in relation with the EMC level requested for his application.

Software recommendations:

The software flowchart must include the management of runaway conditions such as:

- Corrupted program counter
- Unexpected reset
- Critical Data corruption (control registers...)

Prequalification trials:

Most of the common failures (unexpected reset and program counter corruption) can be reproduced by manually forcing a low state on the RESET pin or the Oscillator pins for 1 second.

To complete these trials, ESD stress can be applied directly on the device, over the range of specification values. When unexpected behavior is detected, the software can be hardened to prevent unrecoverable errors occurring (see application note AN1015).

7.9.7 Electrical sensitivity

Table 30. Static latch-up data

Symbol	Parameter	Conditions	Class ⁽¹⁾
LU	Static latch-up class	T _A = +25 °C conforming to JESD78A	II class A

1. Class description: A Class is an STMicroelectronics internal specification. All its limits are higher than the JEDEC specifications, that means when a device belongs to Class A it exceeds the JEDEC standard. B Class strictly covers all the JEDEC criteria (international standard).

7.12 Communication interface electrical characteristics

7.12.1 10/100 Ethernet MAC electrical characteristics

$V_{DDQ} = 2.7 - 3.6 \text{ V}$, $V_{DD} = 1.65 - 2 \text{ V}$, $T_A = -40 / 85 \text{ }^{\circ}\text{C}$ unless otherwise specified.

Ethernet MII interface timings

Figure 25. MII_RX_CLK and MII_TX_CLK timing diagram

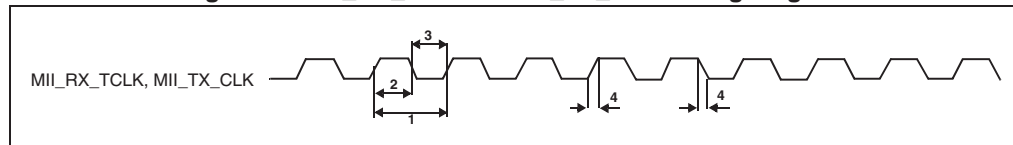


Table 40. MII_RX_CLK and MII_TX_CLK timing table

Symbol	Parameter	Symbol	Value		Unit
			Min	Max	
1	Cycle time	$t_c(\text{CLK})$	40		ns
2	Pulse duration high	$t_{\text{HIGH}}(\text{CLK})$	40%	60%	
3	Pulse duration low	$t_{\text{LOW}}(\text{CLK})$	40%	60%	
4	Transition time	$t_t(\text{CLK})$		1	ns

Figure 26. MDC timing diagram

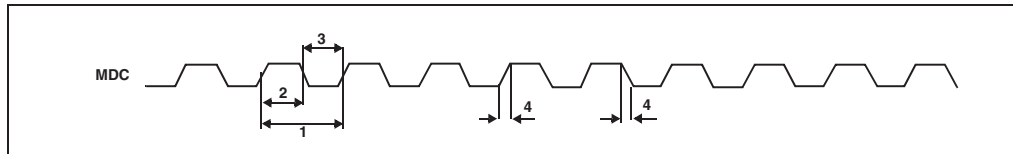


Table 41. MDC timing table

Symbol	Parameter	Symbol	Value		Unit
			Min	Max	
1	Cycle time	$t_c(\text{MDC})$	266		ns
2	Pulse duration high	$t_{\text{HIGH}}(\text{MDC})$	40%	60%	
3	Pulse duration low	$t_{\text{LOW}}(\text{MDC})$	40%	60%	
4	Transition time	$t_t(\text{MDC})$		1	ns

Ethernet MII management timings

Figure 27. Ethernet MII management timing diagram

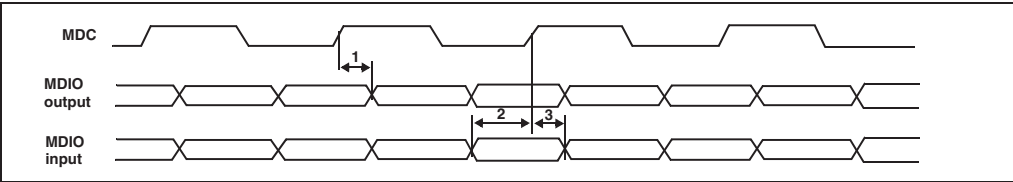


Table 42. Ethernet MII management timing table

Symbol	Parameter	Symbol	Value		Unit
			Min	Max	
1	MDIO delay from rising edge of MDC	$t_c(\text{MDIO})$		2.83	ns
2	MDIO setup time to rising edge of MDC	$T_{su}(\text{MDIO})$	2.70		ns
3	MDIO hold time from rising edge of MDC	$T_h(\text{MDIO})$	-2.03		ns

Ethernet MII transmit timings

Figure 28. Ethernet MII transmit timing diagram

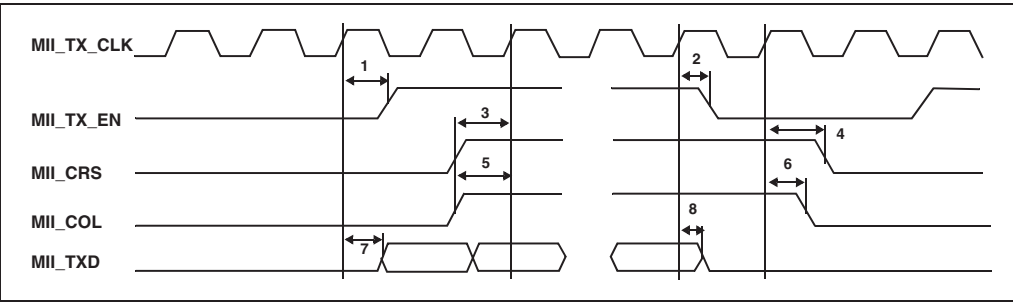


Table 43. Ethernet MII transmit timing table

Symbol	Parameter	Symbol	Value		Unit
			Min	Max	
1	MII_TX_CLK high to MII_TX_EN valid	$t_{VAL}(MII_TX_EN)$		4.20	ns
2	MII_TX_CLK high to MII_TX_EN invalid	$T_{inval}(MII_TX_EN)$		4.86	ns
3	MII_CRS valid to MII_TX_CLK high	$T_{su}(MII_CRS)$	0.61		ns
4	MII_TX_CLK high to MII_CRS invalid	$T_h(MII_CRS)$	0.00		ns
5	MII_COL valid to MII_TX_CLK high	$T_{su}(MII_COL)$	0.81		ns
6	MII_TX_CLK high to MII_COL invalid	$T_h(MII_COL)$	0.00		ns
7	MII_TX_CLK high to MII_TXD valid	$t_{VAL}(MII_TXD)$		5.02	ns
8	MII_TXCLK high to MII_TXD invalid	$T_{inval}(MII_TXD)$		5.02	ns

Ethernet MII receive timings

Figure 29. Ethernet MII receive timing diagram

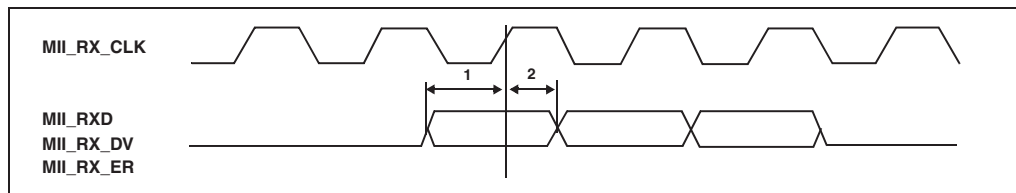


Table 44. Ethernet MII receive timing table

Symbol	Parameter	Symbol	Value		Unit
			Min	Max	
1	MII_RXD valid to MII_RX_CLK high	$T_{su}(MII_RXD)$	0.81		ns
2	MII_RX_CLK high to MII_RXD invalid	$T_h(MII_RXD)$	0.00		ns

7.12.2 USB electrical interface characteristics

USB 2.0 Compliant in Full Speed Mode

7.12.3 CAN interface electrical characteristics

Conforms to CAN 2.0B protocol specification

Table 48. ADC conversion time (silicon Rev G)

Symbol	Parameter ^{(1) (2)}	Test conditions	Value			Unit
			Min	Typ	Max	
t _{CONV(S)}	Single mode conversion time		2*16/f _{ADC}		3*16/f _{ADC}	μs
		f _{ADC} = 24 MHz	1.33		2	
TR(S)	Single mode throughput rate ⁽³⁾	f _{ADC} = 24 MHz			500	ksps
t _{CONV(C)}	Continuous mode conversion time ⁽⁴⁾			1*16/f _{ADC}		μs
		f _{ADC} = 24 MHz		0.66		μs
TR(C)	Continuous mode throughput rate	f _{ADC} = 24 MHz		1500		ksps

1. Guaranteed by design, not tested in production.
2. Parameters in this table apply to devices with silicon Rev G. Refer to [Table 5](#) for device rev identification in OTP memory and to [Section 8: Device marking](#).
3. Value obtained on conversions started by trigger in single mode
4. All successive conversions in continuous and scan modes.

Table 49. ADC conversion time (silicon Rev H and higher)

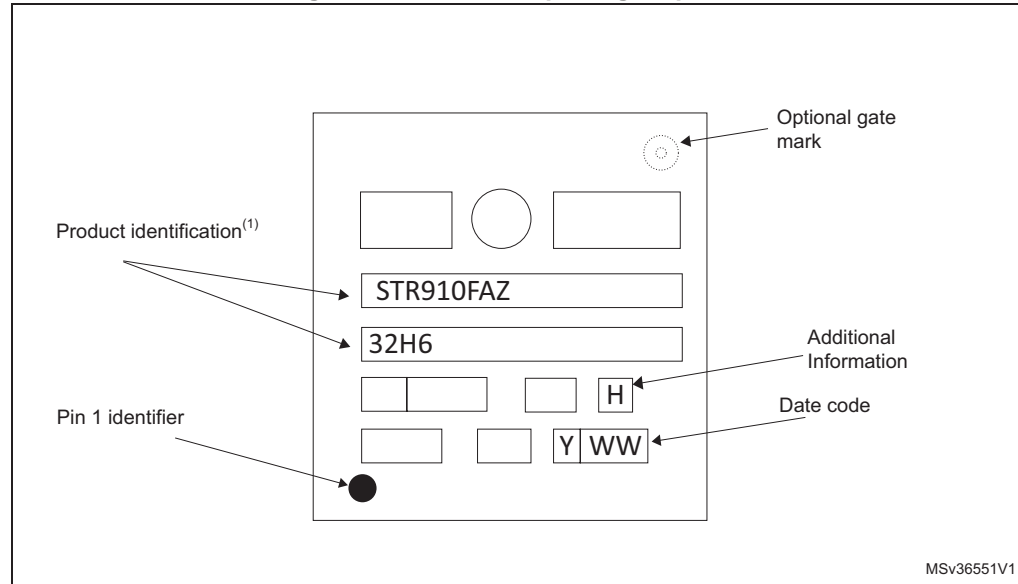
Symbol	Parameter ^{(1) (2)}	Test conditions	Value			Unit
			Min	Typ	Max	
t _{CONV(S)}	Single mode conversion time		1*16/f _{ADC}		2*16/f _{ADC}	μs
		f _{ADC} = 24 MHz	0.66		1.33	
TR(S)	Single mode throughput rate ⁽³⁾	f _{ADC} = 24 MHz			750	ksps
t _{CONV(C)}	Continuous mode conversion time ⁽⁴⁾			1*16/f _{ADC}		μs
		f _{ADC} = 24 MHz		0.66		μs
TR(C)	Continuous mode throughput rate	f _{ADC} = 24 MHz		1500		ksps
t _{CONV(FT)}	Fast trigger mode conversion time ⁽⁵⁾			1*16/f _{ADC}		μs
		f _{ADC} = 24 MHz		0.66		μs
TR(FT)	Fast trigger mode throughput rate ⁽⁶⁾	f _{ADC} = 24 MHz	100		1200	ksps

1. Guaranteed by design, not tested in production.
2. Parameters in this table apply to devices with silicon Rev H and higher. Refer to [Table 5](#) for device rev identification in OTP memory and to [Section 8: Device marking](#).
3. Value obtained from conversions started by trigger in single mode
4. All successive conversions in continuous and scan modes.
5. Conversion started by trigger when automatic clock gated mode enabled. Fast trigger mode is available only in devices with silicon Rev H and higher.
6. Value obtained from conversions started by fast trigger in single mode

Marking of engineering samples for LFBGA144

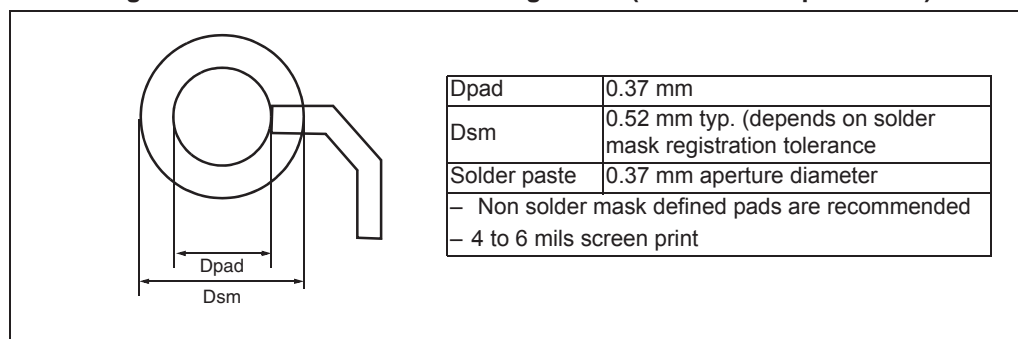
The following figure shows the engineering sample marking for the LFBGA package. Only the information field containing the engineering sample marking is shown.

Figure 46. LFBGA144 package top view



1. Parts marked as "ES", "E" or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering samples to run qualification activity.

Figure 47. Recommended PCB design rules (0.80/0.75 mm pitch BGA)



9.1 ECOPACK

To meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions, and product status are available at www.st.com.

9.2 Thermal characteristics

The average chip-junction temperature, T_J must never exceed 125 °C.

The average chip-junction temperature, T_J , in degrees Celsius, may be calculated using the following equation:

$$T_J = T_A + (P_D \times \Theta_{JA}) \quad (1)$$

Where:

- T_A is the ambient temperature in °C,
- Θ_{JA} is the package junction-to-ambient thermal resistance, in °C/W,
- P_D is the sum of P_{INT} and $P_{I/O}$ ($P_D = P_{INT} + P_{I/O}$),
- P_{INT} is the product of I_{DD} and V_{DD} , expressed in Watts. This is the Chip Internal Power.

$P_{I/O}$ represents the power dissipation on input and output pins;

Most of the time for the applications $P_{I/O} < P_{INT}$ and may be neglected. On the other hand, $P_{I/O}$ may be significant if the device is configured to drive continuously external modules and/or memories. The worst case P_{INT} of the STR91xFA is 500 mW ($I_{DD} \times V_{DD}$, or 250 mA x 2.0 V).

An approximate relationship between P_D and T_J (if $P_{I/O}$ is neglected) is given by:

$$P_D = K / (T_J + 273 \text{ °C}) \quad (2)$$

Therefore (solving equations 1 and 2):

$$K = P_D \times (T_A + 273 \text{ °C}) + \Theta_{JA} \times P_D^2 \quad (3)$$

Where:

- K is a constant for the particular part, which may be determined from equation (3) by measuring P_D (at equilibrium) for a known T_A . Using this value of K, the values of P_D and T_J may be obtained by solving equations (1) and (2) iteratively for any value of T_A .

Table 53. Thermal characteristics

Symbol	Parameter	Value	Unit
Θ_{JA}	Thermal resistance junction-ambient LQFP 80 - 12 x 12 mm / 0.5 mm pitch	41.5	°C/W
Θ_{JA}	Thermal resistance junction-ambient LQFP128 - 14 x 14 mm / 0.4 mm pitch	38	°C/W
Θ_{JA}	Thermal resistance junction-ambient LFBGA 144 - 10 x 10 x 1.7 mm	36.5	°C/W